

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BZX884-C75 Part Description										
								Nexperia DHAM	Zener			
								MCD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects						
			TEST									
			Pre- and Post-Stress									
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below						
		JESD22-A113 Bake Tamb = 125 °C	24 hours									
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours									
# A1	Preconditioning	Reflow soldering	3 cycles	113	9040	0						
	HTRB	MIL-STD-750-1										
		M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet										
# B1	Bias	reverse voltage	1000 hours	138	11040	0						
# DI		MIL-STD-750-1										
		M1038 Method B										
	SSOP	Tj = Tjmax, $Iz = 100%$ of max. datasheet										
# B1b	Steady State Operational	reverse current	1000 hours	20	1600	0						
,, , ,	TC Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000	20	2240							
# A4	remperature cycling	<del>-</del>	1000 cycles	28	2240	0						
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %										
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	28	2240	0						
" 715 aic			30 110013	20	2210							
	H3TRB	JESD22-A101										
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of										
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	28	2240	0						
		MIL-STD-750 Method 1037										
	IOL	ton = toff, devices powered to insure $\Delta Tj$ =										
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	29	2320	0						
	RSH	JESD22-A111										
# C8	Resistance to Solder Heat		10 s	n.a.	n.a.	n.a.						
# C0	SD		10.2	11.a.	11.0.	11.0.						
# C10	Solderability	J-STD-002		63	630	0						

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11040	0	0.38	2.60E+09

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